FAIRCHILD

SEMICONDUCTOR

July 1989 Revised November 1999 74ACQ373 • 74ACTQ373 Quiet Series™ Octal Transparent Latch with 3-STATE Outputs

74ACQ373 • 74ACTQ373 **Quiet Series™ Octal Transparent Latch** with 3-STATE Outputs

General Description

The ACQ/ACTQ373 consists of eight latches with 3-STATE outputs for bus organized system applications. The latches appear transparent to the data when Latch Enable (LE) is HIGH. When LE is LOW, the data satisfying the input timing requirements is latched. Data appears on the bus when the Output Enable (OE) is LOW. When OE is HIGH, the bus output is in the HIGH impedance state.

The ACQ/ACTQ373 utilizes Fairchild Quiet Series™ technology to guarantee quiet output switching and improve dynamic threshold performance. features GTO™ output control and undershoot corrector in addition to a split ground bus for superior performance.

Features

- \blacksquare I_{CC} and I_{OZ} reduced by 50%
- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Guaranteed pin-to-pin skew AC performance
- Improved latch up immunity
- Eight latches in a single package
- 3-STATE outputs drive bus lines or buffer memory address registers
- Outputs source/sink 24 mA
- Faster prop delays than the standard AC/ACT373

Ordering Code:

	= •
M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Body
M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
N20A	20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001m 0.300" Wide
M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Body
M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
MQA20	20-Lead Quarter Size Outline Package (QSOP), JEDEC MO-137, 0.150" Wide
N20A	20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001m 0.300" Wide
	M20D N20A M20B M20D MQA20

Device also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code.

Connection Diagram

GN

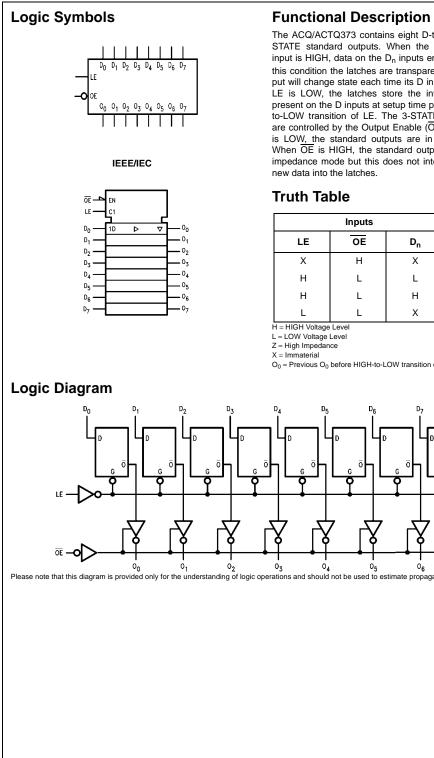
		_	_	
ŌĒ —	1	\bigcirc	20	-v _{cc}
0 ₀ -	2		19	-0 ₇
D ₀ -	3		18	— D ₇
D1-	4		17	— D ₆
01-	5		16	-0 ₆
0 ₂ -	6		15	-0 ₅
D2-	7		14	— D ₅
D3-	8		13	— D4
03-	9		12	-0 ₄
GND —	10		11	-LE
I				

Pin Descriptions

Pin Names	Description
D ₀ -D ₇	Data Inputs
LE	Latch Enable Input
OE	Output Enable Input
O ₀ O ₇	3-STATE Latch Outputs

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Functional Description

The ACQ/ACTQ373 contains eight D-type latches with 3-STATE standard outputs. When the Latch Enable (LE) input is HIGH, data on the D_n inputs enters the latches. In this condition the latches are transparent, i.e., a latch output will change state each time its D input changes. When LE is LOW, the latches store the information that was present on the D inputs at setup time preceding the HIGHto-LOW transition of LE. The 3-STATE standard outputs are controlled by the Output Enable (\overline{OE}) input. When \overline{OE} is LOW, the standard outputs are in the 2-state mode. When \overrightarrow{OE} is HIGH, the standard outputs are in the high impedance mode but this does not interfere with entering

	Inputs					
LE	OE	O _n				
Х	н	Х	Z			
Н	L	L	L			
н	L	н	н			
L	L	х	O ₀			

D-

06

07

delays

 $O_0 = Previous O_0$ before HIGH-to-LOW transition of Latch Enable

Absolute Maximum I	Ratings(Note 1)	Recommended Operat	ing
Supply Voltage (V _{CC})	-0.5V to +7.0V	Conditions	
DC Input Diode Current (I _{IK})		Supply Voltage (V _{CC})	
$V_{I} = -0.5V$	–20 mA	ACQ	2.0V to 6.0V
$V_I = V_{CC} + 0.5V$	+20 mA	ACTQ	4.5V to 5.5V
DC Input Voltage (V _I)	–0.5V to V_{CC} + 0.5V	Input Voltage (V _I)	0V to V _{CC}
DC Output Diode Current (I _{OK})		Output Voltage (V _O)	0V to V _{CC}
$V_{O} = -0.5V$	–20 mA	Operating Temperature (T _A)	$-40^{\circ}C$ to $+85^{\circ}C$
$V_O = V_{CC} + 0.5V$	+20 mA	Minimum Input Edge Rate $\Delta V/\Delta t$	
DC Output Voltage (V _O)	–0.5V to V_{CC} + 0.5V	ACQ Devices	
DC Output Source		V_{IN} from 30% to 70% of V_{CC}	
or Sink Current (I _O)	±50 mA	V _{CC} @ 3.0V, 4.5V, 5.5V	125 mV/ns
DC V_{CC} or Ground Current		Minimum Input Edge Rate $\Delta V / \Delta t$	
per Output Pin (I _{CC} or I _{GND})	±50 mA	ACTQ Devices	
Storage Temperature (T _{STG})	-65°C to +150°C	V _{CC} @ 4.5V, 5.5V	125 mV/ns
DC Latchup Source		Note 1: Absolute maximum ratings are those val	
or Sink Current	±300 mA	to the device may occur. The databook specific out exception, to ensure that the system design	
Junction Temperature (T_J)		supply, temperature, and output/input loading va	ariables. Fairchild does not
PDIP	140°C	recommend operation of FACT™ circuits outside	alabook specifications.

DC Electrical Characteristics for ACQ

Symbol	Parameter	v _{cc}	T _A = -	+25°C	$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$	Units	Conditions	
Symbol		(V)	Тур			Units	Conditions	
VIH	Minimum HIGH Level	3.0	1.5	2.1	2.1		V _{OUT} = 0.1V	
	Input Voltage	4.5	2.25	3.15	3.15	V	or V _{CC} – 0.1V	
		5.5	2.75	3.85	3.85			
VIL	Maximum LOW Level	3.0	1.5	0.9	0.9		$V_{OUT} = 0.1V$	
	Input Voltage	4.5	2.25	1.35	1.35	V	or $V_{CC} - 0.1V$	
		5.5	2.75	1.65	1.65			
V _{OH}	Minimum HIGH Level	3.0	2.99	2.9	2.9			
	Output Voltage	4.5	4.49	4.4	4.4	V	$I_{OUT} = -50 \ \mu A$	
		5.5	5.49	5.4	5.4			
							$V_{IN} = V_{IL} \text{ or } V_{IH}$	
		3.0		2.56	2.46		$I_{OH} = -12 \text{ mA}$	
		4.5		3.86	3.76	V	$I_{OH} = -24 \text{ mA}$	
		5.5		4.86	4.76		$I_{OH} = -24 \text{ mA}$ (Note 2)	
V _{OL}	Maximum LOW Level	3.0	0.002	0.1	0.1			
	Output Voltage	4.5	0.001	0.1	0.1	V	$I_{OUT} = 50 \ \mu A$	
		5.5	0.001	0.1	0.1			
							$V_{IN} = V_{IL} \text{ or } V_{IH}$	
		3.0		0.36	0.44		$I_{OL} = 12 \text{ mA}$	
		4.5		0.36	0.44	V	$I_{OL} = 24 \text{ mA}$	
		5.5		0.36	0.44		I _{OL} = 24 mA (Note 2)	
I _{IN} (Note 4)	Maximum Input Leakage Current	5.5		± 0.1	± 1.0	μΑ	$V_I = V_{CC}, GND$	
I _{OLD}	Minimum Dynamic	5.5			75		V _{OLD} = 1.65V Max	
I _{OHD}	Output Current (Note 3)	5.5			-75	mA	V _{OHD} = 3.85V Min	
I _{CC} (Note 4)	Maximum Quiescent Supply Current	5.5		4.0	40.0	μA	$V_{IN} = V_{CC}$ or GND	
I _{OZ}	Maximum 3-STATE						$V_I (OE) = V_{IL}, V_{IH}$	
	Leakage Current	5.5		±0.25	±2.5	μA	$V_I = V_{CC}, GND$	
							$V_0 = V_{CC}$, GND	
V _{OLP}	Quiet Output	5.0	1.1	1.5		V	Figure 1, Figure 2	
	Maximum Dynamic V _{OL}	0.0	1.1	1.5		v	(Note 5)(Note 6)	
V _{OLV}	Quiet Output	5.0	-0.6	-1.2		V	Figure 2, Figure 2	
	Maximum Dynamic V _{OL}	0.0	-0.0	-1.2		v	(Note 5)(Note 6)	

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Symbol Parameter		V _{CC}	$T_A = +25^{\circ}C$ $T_A = -40^{\circ}C \text{ to } +85^{\circ}C$		$T_{A}=-40^{\circ}C$ to $+85^{\circ}C$	Units	Conditions	
0,		(V)	Тур	Guaranteed Limits		•		
V _{IHD}	Minimum HIGH Level Dynamic Input Voltage	5.0	3.1	3.5		V	(Note 5)(Note 7)	
VILD	Maximum LOW Level Dynamic Input Voltage	5.0	1.9	1.5		V	(Note 5)(Note 7)	

Note 2: All outputs loaded; thresholds on input associated with output under test.

Note 3: Maximum test duration 2.0 ms, one output loaded at a time.

Note 4: $I_{\rm IN}$ and $I_{\rm CC}$ @ 3.0V are guaranteed to be less than or equal to the respective limit @ 5.5V V_{CC}.

Note 5: DIP package.

Note 6: Max number of outputs defined as (n). Data inputs are driven 0V to 5V. One output @ GND.

Note 7: Max number of data inputs (n) switching. (n–1) inputs switching 0V to 5V (ACQ). Input-under-test switching: 5V to threshold (V_{ILD}), 0V to threshold (V_{ILD}), f = 1 MHz.

DC Electrical Characteristics for ACTQ

Symbol	Parameter	V_{CC} $T_A = +25^{\circ}C$ $T_A = -$		$T_A = -40^{\circ}C$ to $+85^{\circ}C$	Units	Conditions	
Symbol		(V)	Тур	Gu	aranteed Limits	Units	Conditions
V _{IH}	Minimum HIGH Level	4.5	1.5	2.0	2.0	V	V _{OUT} = 0.1V
	Input Voltage	5.5	1.5	2.0	2.0	v	or V _{CC} – 0.1V
V _{IL}	Maximum LOW Level	4.5	1.5	0.8	0.8	V	$V_{OUT} = 0.1V$
	Input Voltage	5.5	1.5	0.8	0.8	v	or $V_{CC} - 0.1V$
V _{OH}	Minimum HIGH Level	4.5	4.49	4.4	4.4	V	I _{OUT} = -50 μA
	Output Voltage	5.5	5.49	5.4	5.4	v	$I_{OUT} = -50 \mu A$
	Ē						$V_{IN} = V_{IL} \text{ or } V_{IH}$
		4.5		3.86	3.76	V	$I_{OH} = -24 \text{ mA}$
		5.5		4.86	4.76		I _{OH} = -24 mA (Note 8)
V _{OL}	Maximum LOW Level	4.5	0.001	0.1	0.1	V	I _{OUT} = 50 μA
	Output Voltage	5.5	0.001	0.1	0.1	v	100T - 30 μA
							$V_{IN} = V_{IL} \text{ or } V_{IH}$
		4.5		0.36	0.44	V	$I_{OL} = 24 \text{ mA}$
		5.5		0.36	0.44		I _{OL} = 24 mA (Note 8)
I _{IN} (Note 4)	Maximum Input Leakage Current	5.5		± 0.1	± 1.0	μA	$V_I = V_{CC}, GND$
I _{OZ}	Maximum 3-STATE	5.5		±0.25	±2.5	μA	$V_I = V_{IL}, V_{IH}$
	Leakage Current	5.5		±0.25	±2.0	μΑ	$V_O = V_{CC}, \ GND$
I _{CCT}	Maximum I _{CC} /Input	5.5	0.6		1.5	mA	$V_I = V_{CC} - 2.1V$
I _{OLD}	Minimum Dynamic	5.5			75	mA	V _{OLD} = 1.65V Max
I _{OHD}	Output Current (Note 9)	5.5			-75	mA	V _{OHD} = 3.85V Min
I _{CC} (Note 4)	Maximum Quiescent Supply Current	5.5		4.0	40.0	μA	$V_{IN} = V_{CC}$, or GND
V _{OLP}	Quiet Output	5.0	1.1	1.5		V	Figure 1, Figure 2
	Maximum Dynamic V _{OL}	0.0		1.5		v	(Note 10)(Note 11)
V _{OLV}	Quiet Output	5.0	-0.6	-1.2		V	Figure 1, Figure 2
	Minimum Dynamic V _{OL}	0.0	-0.0	-1.2		v	(Note 10)(Note 11)
V _{IHD}	Minimum HIGH Level	5.0	1.9	2.2		V	(Note 10)(Note 12)
	Dynamic Input Voltage	5.0	1.5	2.2		v	
V _{ILD}	Maximum LOW Level	5.0	1.2	0.8		V	(Note 10)(Note 12)
	Dynamic Input Voltage	0.0	1.2	0.0		v	

Note 8: All outputs loaded; thresholds on input associated with output under test.

Note 9: Maximum test duration 2.0 ms, one output loaded at a time.

Note 10: Plastic DIP package.

Note 11: Max number of outputs defined as (n). Data inputs are driven 0V to 3V. One output @ GND.

Note 12: Max number of data inputs (n) switching. (n–1) inputs switching 0V to 3V (ACTQ). Input-under-test switching: 3V to threshold (V_{ILD}) , 0V to threshold (V_{ILD}) , f = 1 MHz.

AC Electrical Characteristics for ACQ

		V _{CC}		$T_A = +25^{\circ}C$		T _A = -40°	C to +85°C	
Symbol	Parameter	(V)	(V) C _L = 50 pF			C _L =	Units	
		(Note 13)	Min	Тур	Max	Min	Max	
t _{PHL}	Propagation Delay	3.3	2.5	8.0	10.5	2.5	11.0	ns
t _{PLH}	D _n to O _n	5.0	1.5	5.5	7.0	1.5	7.5	
t _{PHL}	Propagation Delay	3.3	2.5	8.0	12.0	2.5	12.5	ns
t _{PLH}	LE to On	5.0	2.0	6.0	8.0	2.0	8.5	115
t _{PZL}	Output Enable Time	3.3	2.5	8.5	13.0	2.5	13.5	
t _{PZH}		5.0	1.5	6.5	8.5	1.5	9.0	ns
t _{PHZ}	Output Disable Time	3.3	1.0	9.0	14.5	1.0	15.0	ns
t _{PLZ}		5.0	1.0	6.5	9.5	1.0	10.0	ns
t _{OSHL}	Output to Output Skew	3.3		1.0	1.5		1.5	ns
tOSLH	D _n to O _n (Note 14)	5.0		0.5	1.0		1.0	ns

Note 13: Voltage Range 5.0 is 5.0V ± 0.5V.

Voltage Range 3.3 is 3.3V \pm 0.3V.

Note 14: Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH-to-LOW (t_{OSHL}) or LOW-to-HIGH (t_{OSLH}). Parameter guaranteed by design.

AC Operating Requirements for ACQ

Symbol	Parameter	V _{CC} (V)	T _A = - C _L =	⊦25°C 50 pF	$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$ $C_L = 50 \text{ pF}$	Units
		(Note 15)	Тур	Guar	anteed Minimum	
t _S	Setup Time, HIGH or LOW	3.3	0	3.0	3.0	22
	D _n to LE	5.0	0	3.0	3.0	ns
t _H	Hold Time, HIGH or LOW	3.3	0	1.5	1.5	
	D _n to LE	5.0	0	1.5	1.5	ns
t _W	LE Pulse Width, HIGH	3.3	2.0	4.0	4.0	22
		5.0	2.0	4.0	4.0	ns

Note 15: Voltage Range 5.0 is 5.0V \pm 0.5V.

Voltage Range 3.3 is 3.3V \pm 0.3V.

AC Electrical Characteristics for ACTQ

Symbol	Parameter	V _{CC} (V)		$T_A = +25^{\circ}C$ $C_1 = 50 \text{ pF}$		$T_{A} = -40^{\circ}C_{I} = 3$	Units	
		(Note 16)	Min	Тур	Max	Min	Max	
t _{PHL}	Propagation Delay	5.0	2.0	6.5	7.5	2.0	8.0	ns
t _{PLH}	D _n to O _n	5.0	2.0	0.5	1.5	2.0	0.0	115
t _{PHL}	Propagation Delay	5.0	2.5	7.0	8.5	2.5	9.0	ns
t _{PLH}	LE to O _n	5.0	2.5				5.0	115
t _{PZL}	Output Enable	5.0	2.0	7.0	9.0	2.0	9.5	ns
t _{PZH}	Time	5.0	2.0	2.0 7.0	3.0	2.0	9.5	
t _{PHZ}	Output Disable	5.0	1.0	8.0	10.0	1.0	10.5	20
t _{PLZ}	Time	5.0	1.0	1.0 8.0	10.0	1.0	10.5	ns
t _{OSHL}	Output to Output Skew	5.0		0.5	1.0		1.0	ns
toslh	D _n to O _n (Note 17)	5.0		0.5	1.0		1.0	ns

Note 16: Voltage Range 5.0 is $5.0V \pm 0.5V$.

Note 17: Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH-to-LOW (t_{OSHL}) or LOW-to-HIGH (t_{OSLH}). Parameter guaranteed by design.

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AC Operating Requirements for ACTQ

Symbol	Parameter	V _{CC} (V) (Note 18)	T _A = +25°C C _L = 50 pF		T _A = -40°C to +85°C C _L = 50 pF	Units
			Тур	Gu	aranteed Minimum	ĺ
t _S	Setup Time, HIGH or LOW	5.0	0	3.0	3.0	ns
	D _n to LE	5.0				
ţн	Hold Time, HIGH or LOW	5.0	0	1.5	1.5	ns
	D _n to LE	5.0				
N	LE Pulse Width, HIGH	5.0	2.0	4.0	4.0	ns

Capacitance

Symbol	Parameter	Тур	Units	Conditions
C _{IN}	Input Capacitance	4.5	pF	V _{CC} = OPEN
C _{PD}	Power Dissipation Capacitance	44.0	pF	$V_{CC} = 5.0V$

FACT Noise Characteristics

The setup of a noise characteristics measurement is critical to the accuracy and repeatability of the tests. The following is a brief description of the setup used to measure the noise characteristics of FACT.

Equipment:

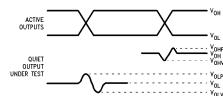
Hewlett Packard Model 8180A Word Generator

PC-163A Test Fixture

Tektronics Model 7854 Oscilloscope

Procedure:

- 1. Verify Test Fixture Loading: Standard Load 50 pF, 500 Ω .
- Deskew the HFS generator so that no two channels have greater than 150 ps skew between them. This requires that the oscilloscope be deskewed first. It is important to deskew the HFS generator channels before testing. This will ensure that the outputs switch simultaneously.
- Terminate all inputs and outputs to ensure proper loading of the outputs and that the input levels are at the correct voltage.
- Set the HFS generator to toggle all but one output at a frequency of 1 MHz. Greater frequencies will increase DUT heating and effect the results of the measurement.
- Set the HFS generator input levels at 0V LOW and 3V HIGH for ACT devices and 0V LOW and 5V HIGH for AC devices. Verify levels with an oscilloscope.



Note A: V_{OHV} and V_{OLP} are measured with respect to ground reference. Note B: Input pulses have the following characteristics:

 $f=1\ MHz,\ t_r=3\ ns,\ t_f=3\ ns,\ skew<150\ ps.$

FIGURE 1. Quiet Output Noise Voltage Waveforms

 V_{OLP}/V_{OLV} and V_{OHP}/V_{OHV} :

- Determine the quiet output pin that demonstrates the greatest noise levels. The worst case pin will usually be the furthest from the ground pin. Monitor the output voltages using a 50 Ω coaxial cable plugged into a standard SMB type connector on the test fixture. Do not use an active FET probe.
- Measure V_{OLP} and V_{OLV} on the quiet output during the worst case transition for active and enable. Measure V_{OHP} and V_{OHV} on the quiet output during the worst case active and enable transition.
- Verify that the GND reference recorded on the oscilloscope has not drifted to ensure the accuracy and repeatability of the measurements.

V_{ILD} and V_{IHD}:

- Monitor one of the switching outputs using a 50Ω coaxial cable plugged into a standard SMB type connector on the test fixture. Do not use an active FET probe.
- First increase the input LOW voltage level, V_{IL}, until the output begins to oscillate or steps out a min of 2 ns. Oscillation is defined as noise on the output LOW level that exceeds V_{IL} limits, or on output HIGH levels that exceed V_{IH} limits. The input LOW voltage level at which oscillation occurs is defined as V_{ILD}.
- Next decrease the input HIGH voltage level, V_{IH} until the output begins to oscillate or steps out a min of 2 ns. Oscillation is defined as noise on the output LOW level that exceeds V_{IL} limits, or on output HIGH levels that exceed V_{IH} limits. The input HIGH voltage level at which oscillation occurs is defined as V_{IHD}.
- Verify that the GND reference recorded on the oscilloscope has not drifted to ensure the accuracy and repeatability of the measurements.

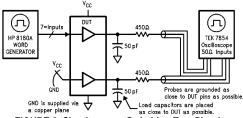
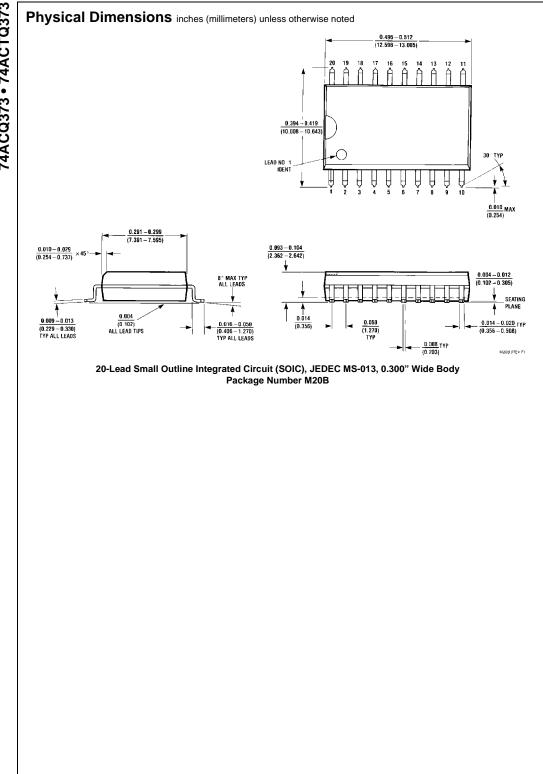
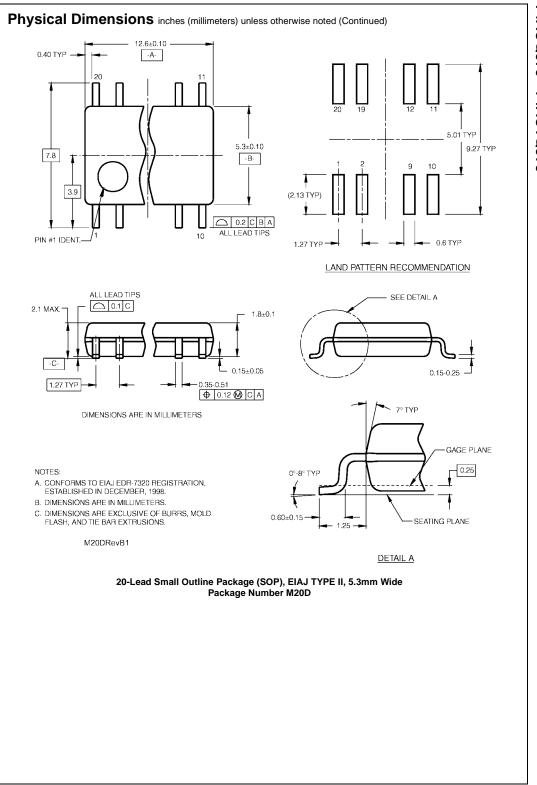
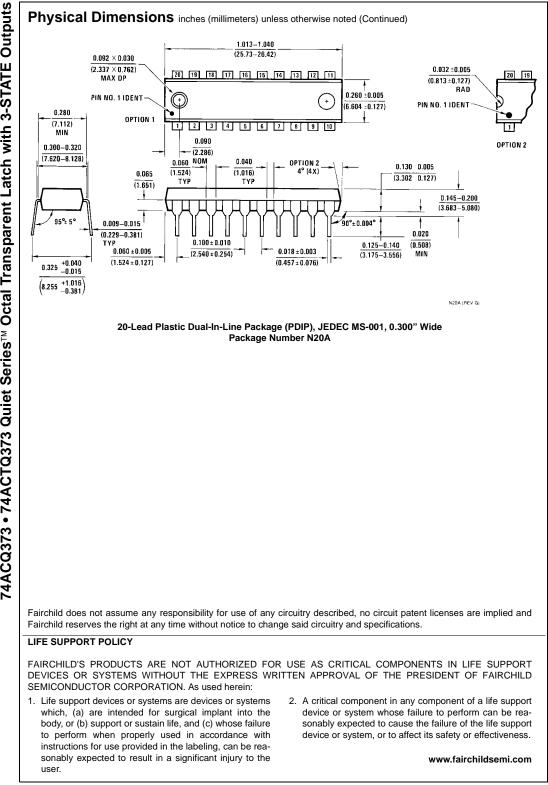


FIGURE 2. Simultaneous Switching Test Circuit





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